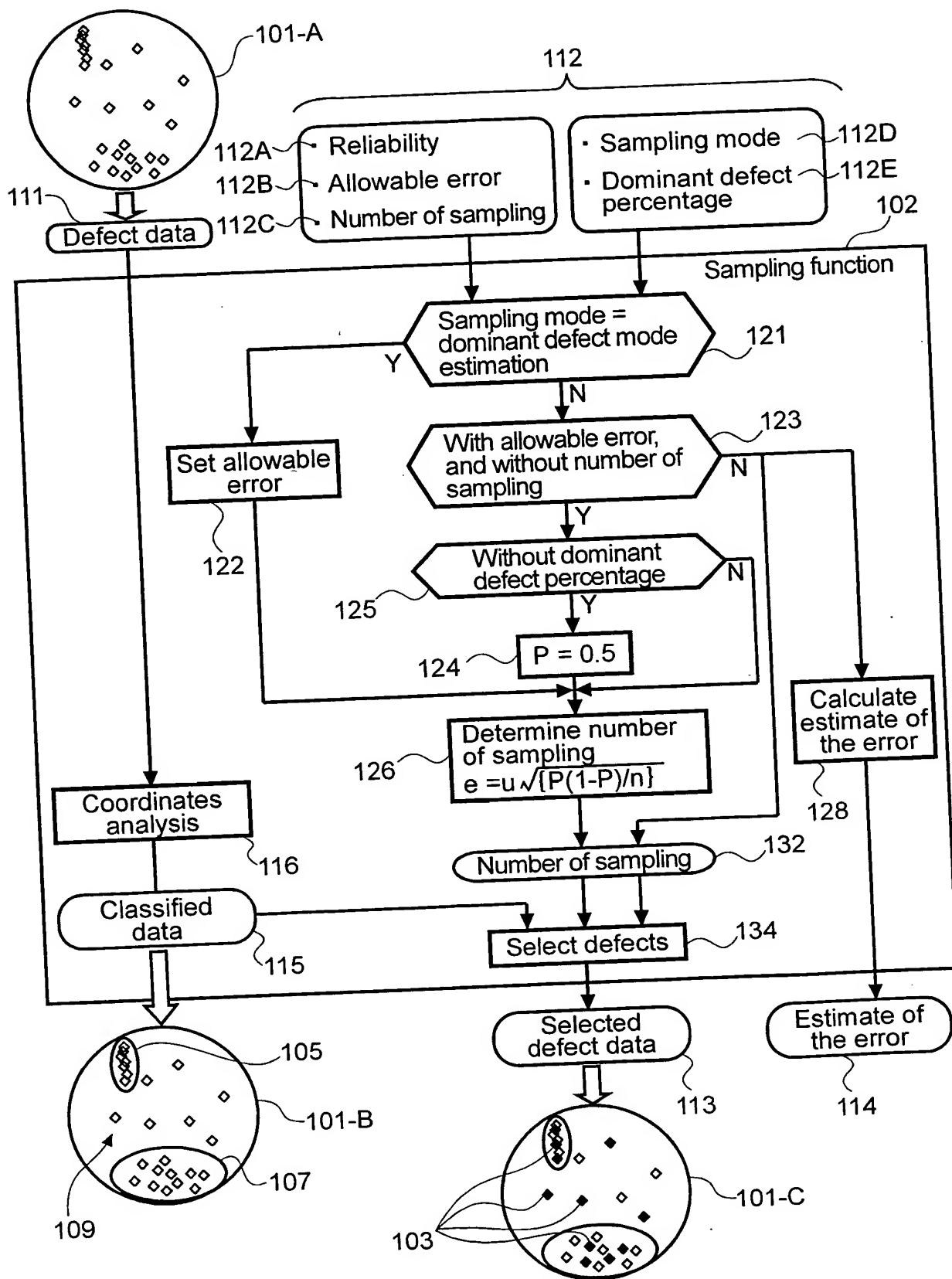


FIG.1



Reliability	U
0.80	1.28
0.90	1.65
0.98	2.33
...	...

FIG. 3

FIG. 3

302

324

322

332

336

U=2.33

U=1.65

U=1.28

P

n

	0.1	0.2	0.3	0.4	0.5	0.6	0.7	0.8	0.9
0.05	59	105	138	158	164	158	138	105	59
0.10	15	26	35	39	41	39	35	26	15
0.20	4	7	9	10	10	10	9	7	4
...

334

FIG.4

Reliability

%

Whole wafer

Classified Regions

High Density

Dense

Sparse

Sampling mode

▼

D.D. %

%

error %

%

Samples

Pts.

OK

CANCEL

FIG. 5

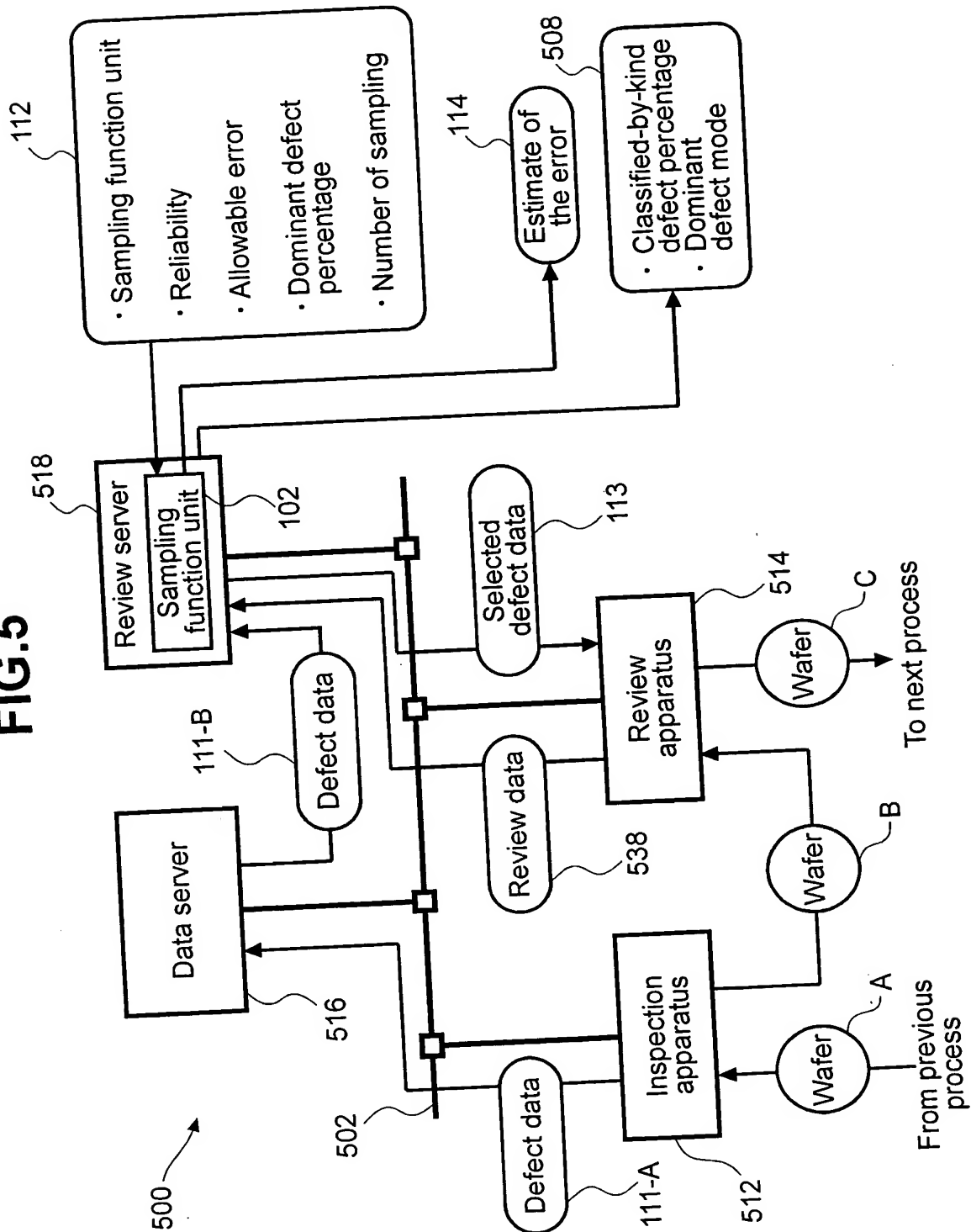
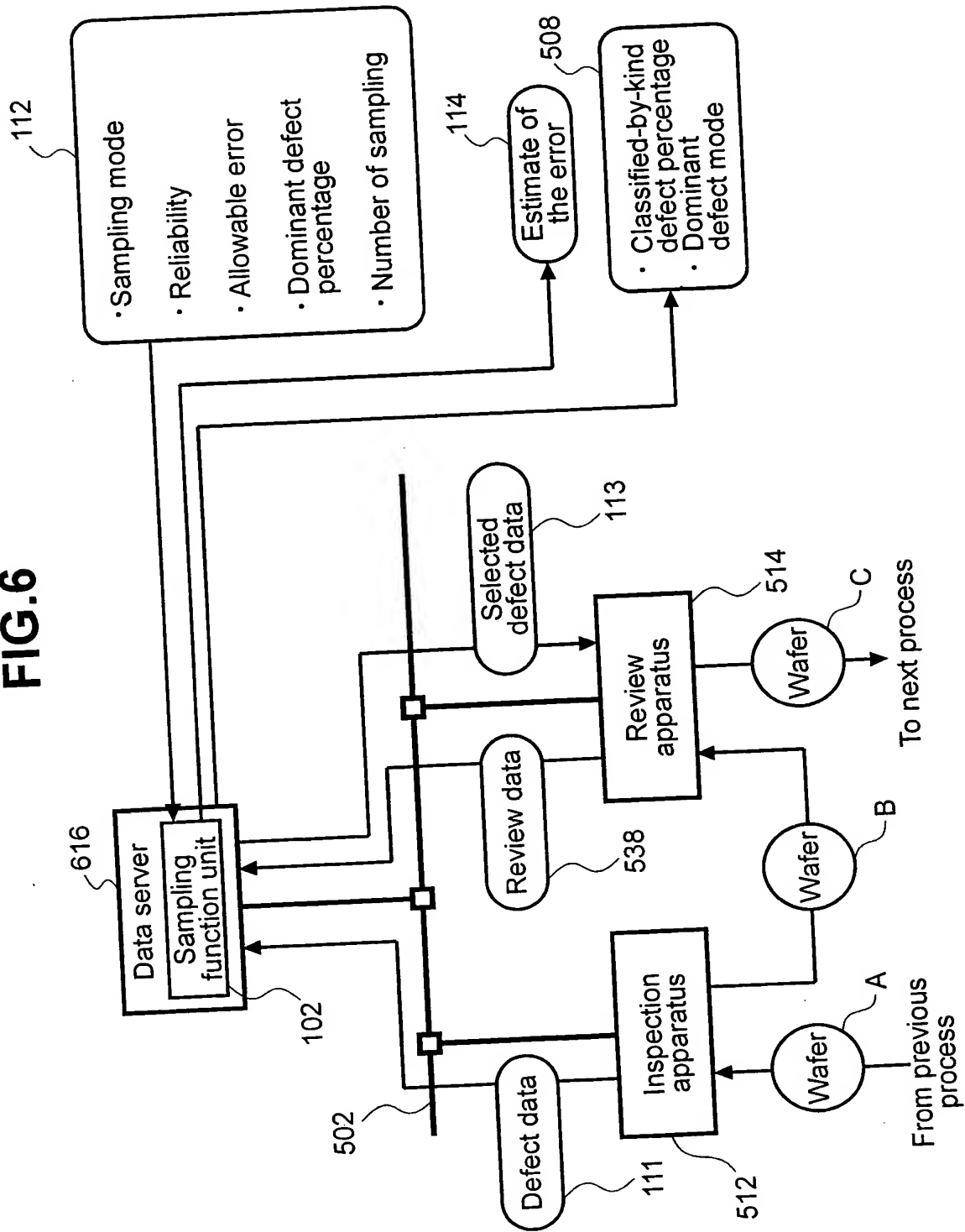


FIG. 6



112

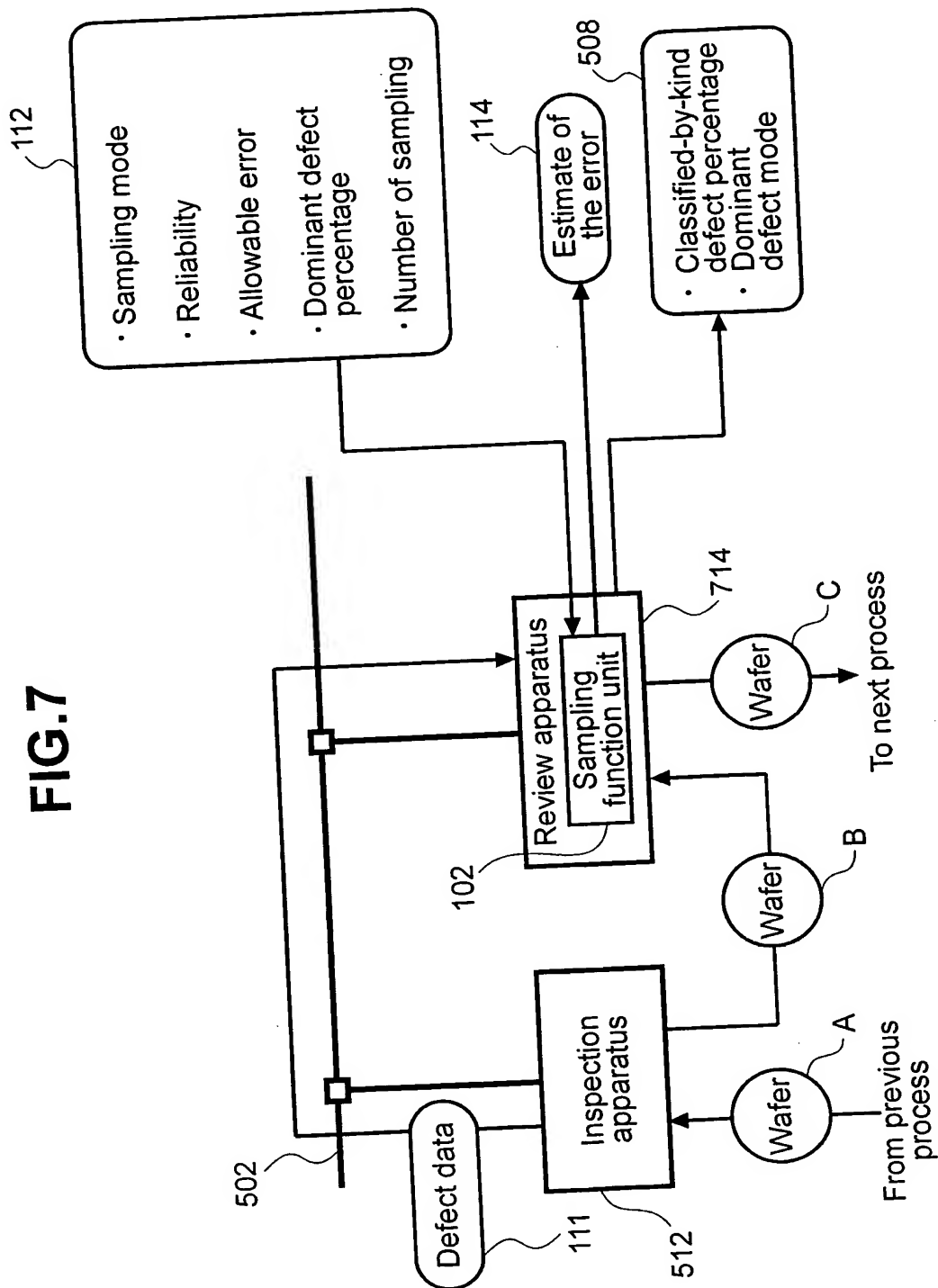


FIG. 8

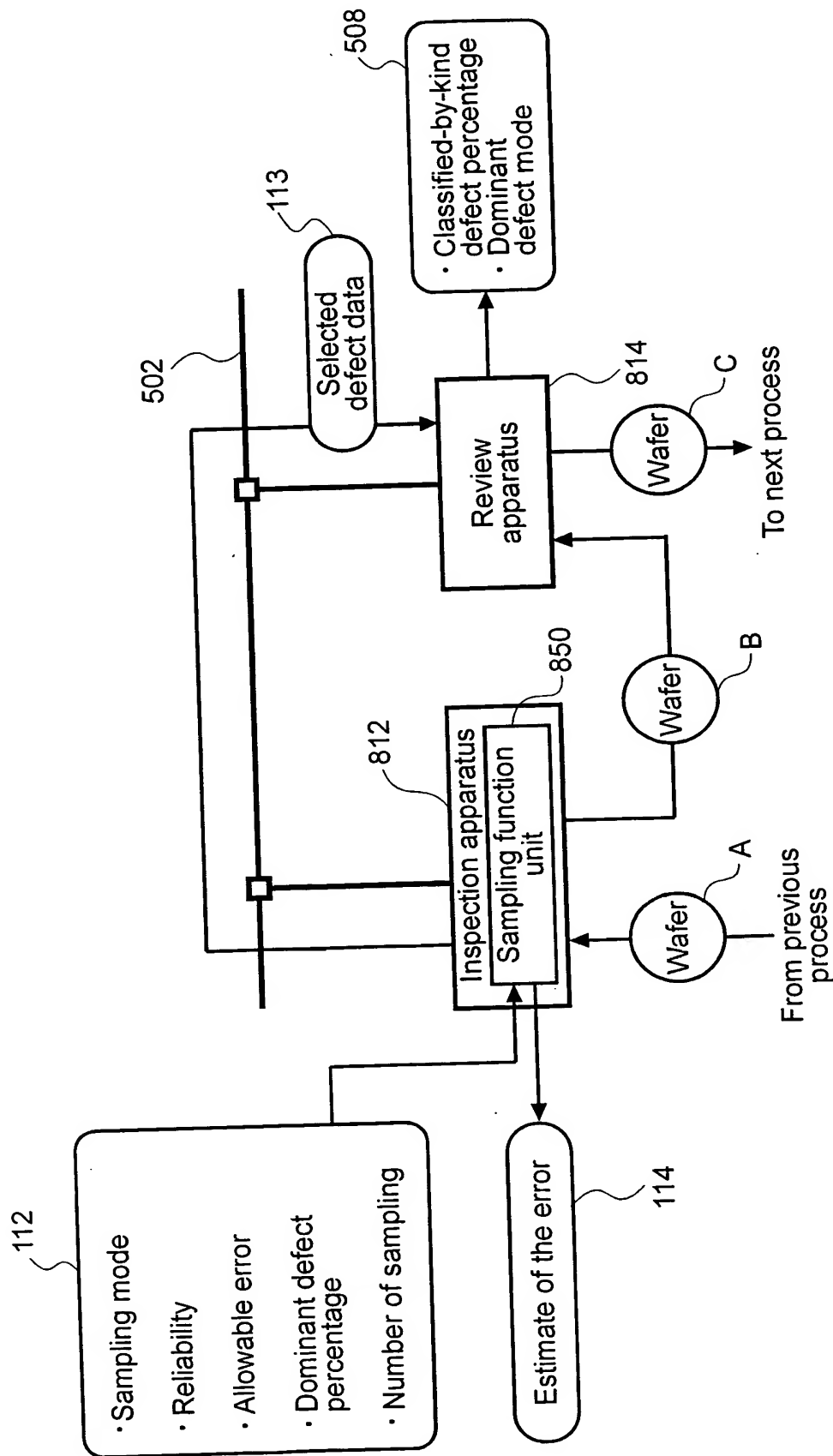


FIG. 9

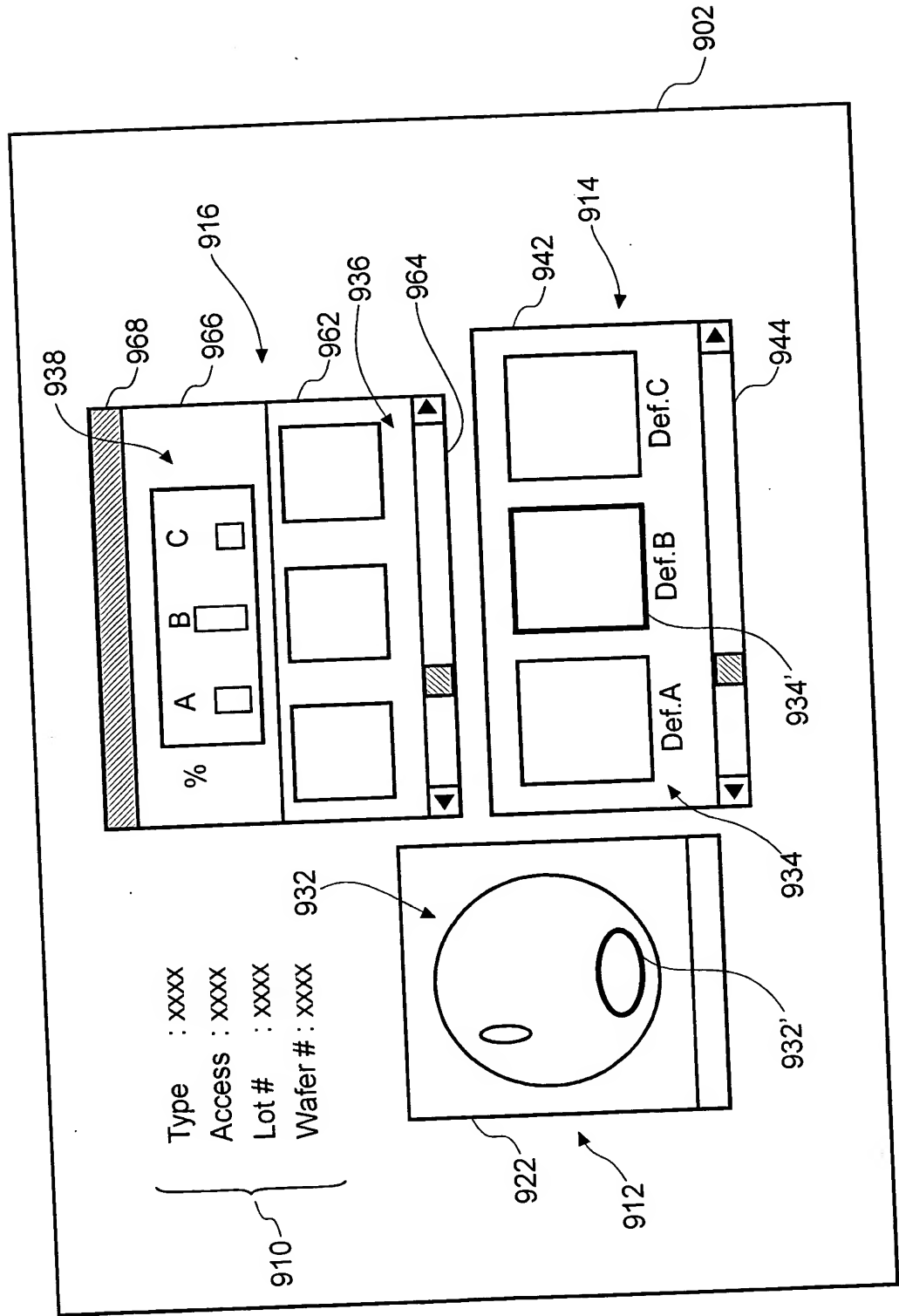
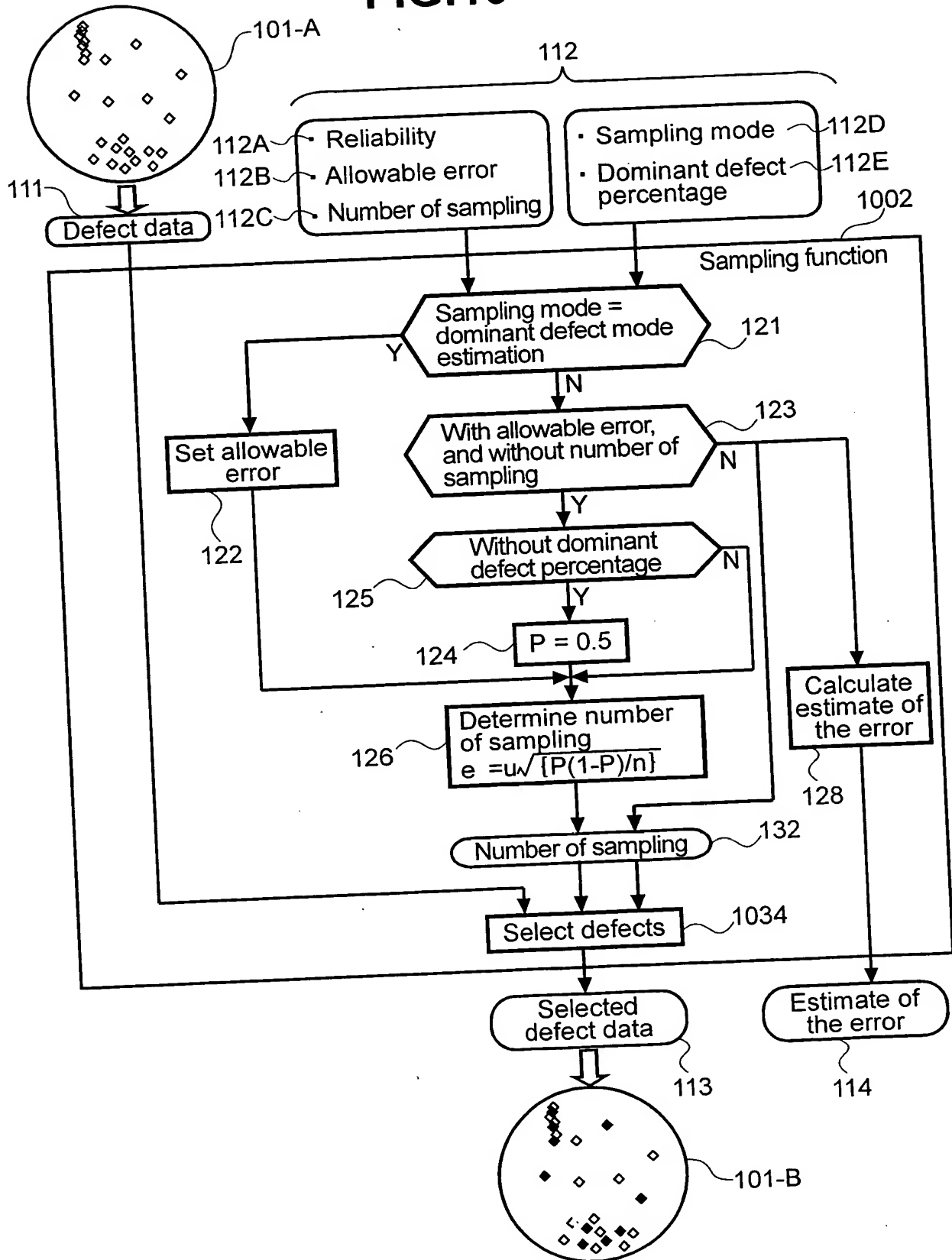


FIG.10



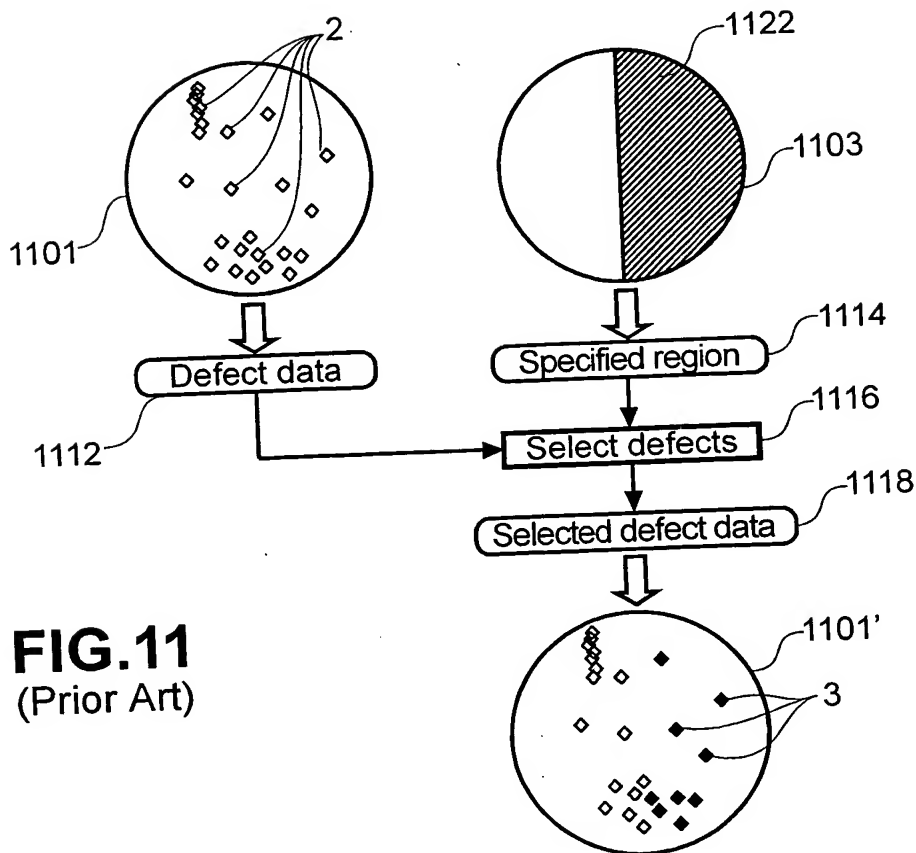


FIG. 11
 (Prior Art)

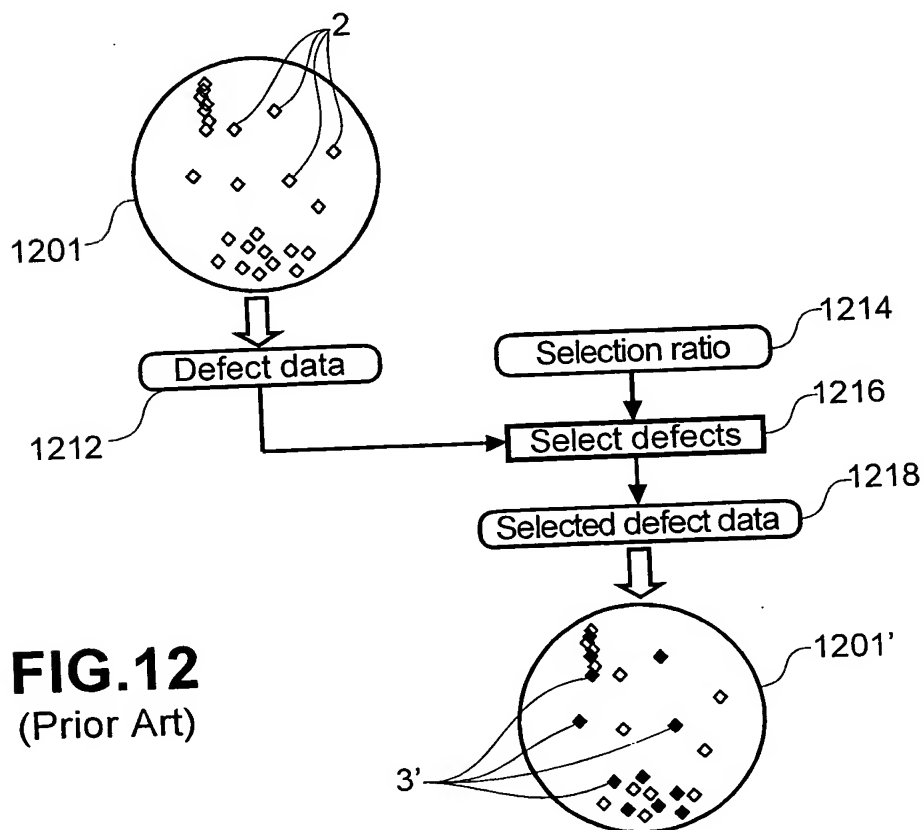


FIG. 12
 (Prior Art)